

Policy decision in ESCC. Proposed text as in attached draft

DOCUMENT CHANGE REQUEST

1294 DCR number Changes required for: Qualification Originator: Fernando Martinez Date: 2020/07/17 Date sent: 2019/09/06 Organisation: ESTEC Status: IMPLEMENTED Title: Generic Specification for Discrete Semiconductor Components Number: 5000 Issue: 8 Other documents affected: Page: 11 Paragraph: New paragraph 4.2.1 Original wording: Proposed wording: New paragraph inserts Single Phase Qualfiication (SPQ) as a possibility for discrete devices Justification:



4.2.1

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missing references are necessary for implementation of Qualification

reference to replacement of specs and test methods is consistent with other ESCC Generic specs

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